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<table>
<thead>
<tr>
<th>Topic</th>
<th>Documents</th>
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<tbody>
<tr>
<td>CMOS</td>
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<td>RRAM/MRAM</td>
<td>5,400+</td>
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<tr>
<td>Optoelectronics/OEIC Applications</td>
<td>49,500+</td>
</tr>
<tr>
<td>Semiconductor Lasers</td>
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<tr>
<td>3D IC</td>
<td>4,500+</td>
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<tr>
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<td>9,200+</td>
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<td>Plasmons</td>
<td>11,400+</td>
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<td>Artificial Intelligence</td>
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<tr>
<td>Internet of Things/M2M</td>
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—IEEE Journal of Solid-State Circuits

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IEEE International Semiconductor Laser Conference
IEEE Semiconductor Thermal Measurement and Management Symposium
IEEE Symposium on Compound Semiconductor Integrated Circuit
IEEE Symposium on Semiconductor Thermal Measurement and Management
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International Conference on Advanced Semiconductor Devices and Microsystems
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International Conference on Semiconductor Laser and Photonics
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International Semiconductor Device Research Symposium
International Symposium on Power Semiconductor Devices and ICs
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International Symposium on Semiconductor Manufacturing

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IEC 62526 edition 1.0 2007 Standard for Extensions to Standard Test Interface Language (STIL) for Semiconductor Design Environments
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